

Marjorie A Olmstead

List of Publications by Year in descending order

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#	ARTICLE	IF	CITATIONS
1	Group III selenides: Controlling dimensionality, structure, and properties through defects and heteroepitaxial growth. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 2021, 39, 020801.	0.9	2
2	Variation of Band Gap and Lattice Parameters of $\text{Pb}(\text{Al}_{1-x}\text{Ga}_x)_2\text{O}_3$ Powder Produced by Solution Combustion Synthesis. <i>Journal of the American Ceramic Society</i> , 2016, 99, 2467-2473.	1.9	87
3	Polaronic conduction and Anderson localization in reduced strontium barium niobate. <i>Applied Physics Letters</i> , 2015, 107, 232901.	1.5	9
4	Site occupancy and cation binding states in reduced polycrystalline $\text{SrBaLaNb}_2\text{O}_6$. <i>Applied Physics Letters</i> , 2014, 104, 101607.	1.5	13
5	Sputtering-induced CoO formation in x-ray photoelectron spectroscopy of nanocrystalline $\text{Zn}_{1-x}\text{Co}_x\text{O}$ spinodal enrichment models. <i>Journal of Applied Physics</i> , 2010, 107, 103917.	1.1	7
6	Laser and electrical current induced phase transformation of AlIn_2Se_3 semiconductor thin film on Si(111). <i>Applied Physics A: Materials Science and Processing</i> , 2008, 93, 93-98.	1.1	18
7	Heteroepitaxial growth of the intrinsic vacancy semiconductor $\text{Al}_{1-x}\text{Ga}_x\text{Si}$ on Si(111): Initial structure and morphology. <i>Physical Review B</i> , 2008, 78, .	1.1	8
8	Semiconducting chalcogenide buffer layer for oxide heteroepitaxy on Si(001). <i>Applied Physics Letters</i> , 2006, 88, 181903.	1.5	8
9	Influence of perovskite termination on oxide heteroepitaxy. <i>Journal of Applied Physics</i> , 2006, 99, 113521.	1.1	10
10	Contrast in scanning probe microscopy images of ultrathin insulator films. <i>Applied Physics Letters</i> , 2006, 88, 063107.	1.5	5
11	Chemical passivity of III-VI bilayer terminated Si(111). <i>Applied Physics Letters</i> , 2005, 87, 171906.	1.5	9
12	Intrinsic Vacancy-Induced Nanoscale Wire Structure in Heteroepitaxial $\text{Ga}_2\text{Se}_3/\text{Si}(001)$. <i>Physical Review Letters</i> , 2005, 94, 116102.	2.9	19
13	Electronic structure evolution during the growth of ultrathin insulator films on semiconductors: From interface formation to bulklike $\text{CaF}_2/\text{Si}(111)$ films. <i>Physical Review B</i> , 2005, 72, .	1.1	11
14	Heterointerface formation of aluminum selenide with silicon: Electronic and atomic structure of $\text{Si}(111):\text{AlSe}$. <i>Physical Review B</i> , 2005, 71, .	1.1	16
15	Electronic structure of the $\text{Si}(111):\text{GaSe}$ van der Waals-like surface termination. <i>New Journal of Physics</i> , 2005, 7, 108-108.	1.2	18
16	Atomically resolved imaging of a CaF bilayer on $\text{Si}(111)$: Subsurface atoms and the image contrast in scanning force microscopy. <i>Physical Review B</i> , 2004, 69, .	1.1	13
17	Atomic structures of defects at $\text{GaSe}/\text{Si}(111)$ heterointerfaces studied by scanning tunneling microscopy. <i>Physical Review B</i> , 2004, 69, .	1.1	18
18	Low-energy photoelectron diffraction structure determination of GaSe -bilayer-passivated $\text{Si}(111)$. <i>Physical Review B</i> , 2001, 64, .	1.1	14

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19	Interaction of Se and GaSe with Si(111). <i>Physical Review B</i> , 2000, 61, 7215-7218.	1.1	39
20	Epitaxial growth of laminar crystalline silicon on CaF ₂ . <i>Applied Physics Letters</i> , 2000, 77, 1289-1291.	1.5	15
21	Heteroepitaxy of Disparate Materials: From Chemisorption to Epitaxy in CaF ₂ /Si(111). <i>Series on Directions in Condensed Matter Physics</i> , 1999, , 211-266.	0.1	25
22	Altered photoemission satellites at CaF ₂ - and SrF ₂ -on-Si(111) interfaces. <i>Physical Review B</i> , 1996, 53, 1584-1593.	1.1	5
23	Growth kinetics of CaF ₂ /Si(111) heteroepitaxy: An x-ray photoelectron diffraction study. <i>Physical Review B</i> , 1995, 51, 5352-5365.	1.1	62
24	Role of Step and Terrace Nucleation in Heteroepitaxial Growth Morphology: Growth Kinetics of CaF ₂ /Si(111). <i>Physical Review Letters</i> , 1995, 75, 2380-2383.	2.9	29
25	Layer-by-layer resolved core-level shifts in CaF ₂ and SrF ₂ on Si(111): Theory and experiment. <i>Physical Review B</i> , 1994, 50, 11052-11069.	1.1	27
26	Surface core-level shifts in CaF ₂ -on-Si(111) films: Experiment and theory. <i>Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena</i> , 1993, 11, 1444.	1.6	15
27	Variable growth modes of CaF ₂ on Si(111) determined by x-ray photoelectron diffraction. <i>Applied Physics Letters</i> , 1993, 62, 2057-2059.	1.5	29
28	CaF ₂ -Si(111) as a model ionic-covalent system: Transition from chemisorption to epitaxy. <i>Physical Review B</i> , 1993, 48, 5716-5719.	1.1	23
29	Kinetic Control of CaF ₂ on Si(111) Growth Morphology. <i>Materials Research Society Symposia Proceedings</i> , 1993, 312, 207.	0.1	0
30	Local-field corrections to surface and interface core-level shifts in insulators. <i>Physical Review B</i> , 1992, 46, 12884-12887.	1.1	16
31	Atomic-size effects on the growth of SrF ₂ and (Ca,Sr)F ₂ on Si(111). <i>Physical Review B</i> , 1991, 43, 7335-7338.	1.1	7
32	Role of lattice mismatch and surface chemistry in the formation of epitaxial semiconductor-insulator interfaces. <i>Physical Review B</i> , 1990, 41, 8420-8430.	1.1	20
33	Bonding of Se and ZnSe to the Si(100) surface. <i>Physical Review B</i> , 1989, 39, 12985-12988.	1.1	60
34	Semiconductor Surfaces and Interfaces Studied with Synchrotron Radiation. , 1989, , 285-334.		0
35	Electronic and Atomic Structure of GaAs Epitaxial Overlays on Si(111). <i>Physical Review Letters</i> , 1988, 61, 2957-2960.	2.9	15
36	Chemical Bonding and Lattice Mismatch in Semiconductor/insulator Heteroepitaxy: SrF ₂ on Si(111). <i>Materials Research Society Symposia Proceedings</i> , 1988, 116, 419.	0.1	1

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37	Electronic structure, atomic structure, and the passivated nature of the arsenic-terminated Si(111) surface. <i>Physical Review B</i> , 1987, 35, 3945-3951.	1.1	205
38	Photoemission study of bonding at the CaF ₂ -on-Si(111) interface. <i>Physical Review B</i> , 1987, 35, 7526-7532.	1.1	162
39	Formation of the interface between GaAs and Si: Implications for GaAs on Si heteroepitaxy. <i>Applied Physics Letters</i> , 1987, 51, 523-525.	1.5	50
40	Optical properties and atomic structure of cleaved silicon and germanium (111) surfaces. <i>Surface Science Reports</i> , 1986, 6, 159-252.	3.8	52
41	Initial formation of the interface between a polar insulator and a nonpolar semiconductor: CaF ₂ on Si(111). <i>Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena</i> , 1986, 4, 1123.	1.6	89
42	Theory of the temperature dependence of Si(111)2 \times 1 surface-state optical absorption. <i>Physical Review B</i> , 1986, 33, 8402-8409.	1.1	18
43	Arsenic overlayer on Si(111): Removal of surface reconstruction. <i>Physical Review B</i> , 1986, 34, 6041-6044.	1.1	171
44	Temperature dependence of the Si and Ge (111)2 \times 1 surface-state optical absorption. <i>Physical Review B</i> , 1986, 33, 2564-2573.	1.1	19
45	Polarization Dependent Ge and Si (111)2 \times 1 Surface State Optical Absorption: A Test of surface Reconstruction Models. , 1985, , 21-26.		0
46	Direct Measurement of the Polarization Dependence of Si(111)2 \times 1 Surface-State Absorption by Use of Photothermal Displacement Spectroscopy. <i>Physical Review Letters</i> , 1984, 52, 1148-1151.	2.9	159
47	Polarization dependence of Ge(111)2 \times 1 surface-state absorption using photothermal displacement spectroscopy: A test of surface reconstruction models. <i>Physical Review B</i> , 1984, 29, 7048-7050.	1.1	39
48	A novel method for the study of optical properties of surfaces. <i>Surface Science</i> , 1983, 132, 68-72.	0.8	18
49	A new probe of the optical properties of surfaces. <i>Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena</i> , 1983, 1, 751.	1.6	39